

Application/Control	No. Applicant(s) Reexaminat	/Patent under ion
10/617,956	PERIYALW	'AR ET AL.
Examiner	Art Unit	
Tu X. Nguyen	2618	

SEARCHED					
Class	Subclass	Date	Examiner		
455	11.1	1/4/2007	TN		
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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